Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/252,925	OHNISHI ET AL.	
Examiner	Art Unit	_
Hanh Nguyen	2668	

SEARCHED				
Class	Subclass	Date	Examiner	
370	400	11/10/2005	HN	
	395.1			
	395.6			
	474			
	397			
	396			
	389			
709	227			
709	228			
		300		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
370	397	11/10/2005	HN	
	474			
709	227			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST	11/10/2005	HN	
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